

## Form 1449 (Modified)

Information Disclosure  
Statement By Applicant

Atty Docket No. INT 8899C1  
 Application No.: 09/09,053  
 Inventor BAKER, et al  
 Group 2612  
 Filing Date January 12, 2001

## U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- Class	Filing Date
LN	A	3,946,696	3/76	Lubnow	114	221R	
	B	4,418,993	12/6/83	Lipton			5/7/81
	C	4,717,958	1/98	Gal et al	348	208	
	D	5,004,328	4/2/91	Masayuki et al			9/25/87
	E	5,049,988	9/17/91	Sefton, et al			8/10/89
	F	5,063,441	11/5/91	Lipton et al			10/11/90
	G	5,142,357	8/25/92	Lipton et al			5/9/91
	H	5,206,503	4/27/93	Toops			8/7/91
	I	5,270,861	12/93	Estelle	359	676	
	J	5,402,171	3/28/95	Tagami, et al			9/10/93
	K	5,440,343	8/95	Parulski et al	348	316	
	L	5,453,784	9/95	Krishnan et al	348	348	
	M	5,453,785	9/26/95	Lenhardt et al	348	357	7/28/93
	N	5,548,327	8/96	Tagami et al	348	219	
	O	5,712,483	1/98	Boone et al	250	367	
	P	5,721,608	2/98	Taniguchi	355	53	
	Q	5,812,191	9/98	Orava et al	348	308	
LN	R	5,819,120	10/98	Hamada et al	386	77	

Technology Center 2600

## Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- Class	Translation Yes No
LN	S	GB2210530A	6/7/89	UK			
LN	T	EP0512403A	11/11/92	EPO			X
LN	U	DE4304529C	6/30/94	Germany			X
LN	V	JP07303207A	11/14/95	Japan			X
	W	05288532	11/2/93	Japan			

## Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	X	Isabella T. Lewis, "WFOV Star Tracker Camera," June-1991, SPIE Vol. 1478, OCI Applied Optics, Garden Grove, CA pp. 2-12.
	Y	Hye-Sook Park et al., "Realtime Tracking System for the Wide Field of View Telescope Project," 1989, Lawrence Livermore National Laboratory, SPEI Vol. 1111, pp. 196-203.
	Z	National Defense Research Committee, Optical Research Laboratory-Harvard Univ., Spherically Symmetrical Lenses and Associated Equipment for Wide Angle Aerial Photography, Contract No. OEMsr-474, 6/6/46.
Examiner	Leonahuna Nauen	
	Date Considered	8/4/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Docket No.	Application No.
	INT1P004A	08/989,202
	Applicant: Baker et al.	
	Filing Date 12/12/97	Group 2612

jc974 U.S. PTO  
09/759053  
01/12/01

### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
	A						
	B						
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	L							
	M							
	N							
	O							
	P							

### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	<del>National Defense Research Committee, Optical Research Laboratory</del> <del>Harvard University, Spherically Symmetrical Lenses and Associated</del> <del>Equipment for Wide Angle Aerial Photography, Contract No. OEMsr 474,</del> <del>June 6, 1946</del>
Examiner	Date Considered	
<i>Leonahuenatunen</i>	8/4/04	

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)	Atty Docket No. INT1P899C1 Application No.: 09/759,053 Inventor BAKER, et al Group 2612 Filing Date January 12, 2001
--	--

#### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
LN	A	5,633,491	5/1997	Kasdan	348	79	_____
LN	B	6,204,880	3/2001	Nishimura	348	240.99	_____
	C						
	D						
	E						
	F						
	G						
	H						
	I						
	J						
	K						

RECEIVED

MAR 17 2004

Technology Center 2600

#### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation	
	L						Yes	No
	M							
	N							
	O							
	P							

#### Other Documents

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	R	
	S	
	T	
Examiner	Leonahuna Naveen	
	Date Considered	8/4/04

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.